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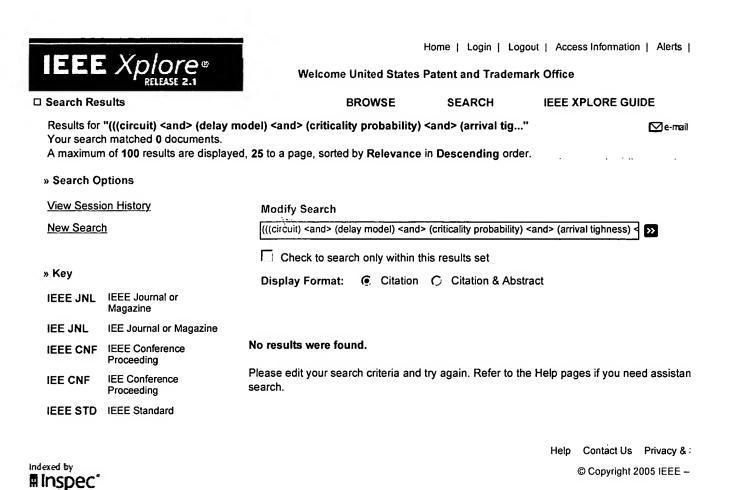
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☐   1. **Timing minimization by statistical timing hMetis-based partitioning**
Ababei, C.; Bazargan, K.;
VLSI Design, 2003. Proceedings. 16th International Conference on
4-8 Jan. 2003 Page(s):58 - 63
Digital Object Identifier 10.1109/ICVD.2003.1183115

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